78-102

Mitamel 2213 11/29/15

208-053-20X CONT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF:

:

CRAIG B. PRATER ET AL

: GROUP: 2212

SERIAL NO: 08/416,100

: EXAMINER: D. LARKIN

FILED: APRIL 4, 1995

.

FOR:

ATOMIC FORCE MICROSCOPE

AND METHOD OF OPERATING AN ATOMIC FORCE MICROSCOPE

RECEIVED

AMENDMENT

ASSISTANT COMMISSIONER OF PATENTS WASHINGTON. DC 20231

GROUP 2200

SIR:

In response to the Official Office Action dated July 20, 1995, please amend the above-identified patent application as follows:

IN THE TITLE

Page 1, lines 2 and 3, delete the existing title and substitute therefor --scanning STYLUS ATOMIC FORCE MICROSCOPE WITH CANTILEVER TRACKING AND OPTICAL ACCESS--.

IN THE SPECIFICATION

Page 2, line 17, after "07/926,175" insert -, now

U.S. Patent No. 5,412,980--;

line 23, change "53(12), Sep. 19, 1988" to

--65(1), Jan. 1, 1989--/

Page 4, line 13, change "Mayer" to --Meyer--;
line 15, change "(12.89)\(\frac{1}{11.50}\), 75 (3.99.3) --.
1 102/ 78.00 CK 5508-053-20X

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